Test Report issued under the responsibility of:





TEST REPORT IEC 60947-2

Low-voltage switchgear and controlgear. Part 2: Circuit-breakers

Date of issue...... 2016-10-14

CB Testing Laboratory...... Shanghai Testing Laboratory...... Shanghai Testing Laboratory......

(STIEE)

Address 505 Wu Ning Rd. Shanghai 200063, P.R. CHINA

Applicant's name...... Zhejiang Tengen Electrics Co., Ltd.

Address TENGEN Industry Zone, Liushi, Yueqing City, Zhejiang

Province, P.R. China

Test specification:

Test procedure: CB scheme

Non-standard test method.....: N/A

Test Report Form No...... IEC60947_2G

Test Report Form(s) Originator: DEKRA Certification BV

Master TRF Dated 2013-11

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Trade Mark TENGEN

Manufacturer Zhejiang Tengen Electrics Co., Ltd.

Model/Type reference...... TGB3Z-63, TGB3Z-63H

Ratings Ue: AC230V(1P), AC400V(2P,3P,4P),

DC80V(1P appearance),DC125V(2P appearance)

In: 1, 2, 3, 4, 5, 6, 10, 16, 20, 25, 32, 40, 50, 63A

Testing procedure and testing location:			
□ CB Testing Laboratory:		Shanghai Testing & Inspection Institute for Electrical Equipment (STIEE)	
Testing location/ address		505 Wu Ning Rd. Shanghai 200063, P.R. CHINA	
Test	ed by (name + signature):	Cui Tao	在· 陆 魏 秋媛
Арр	roved by (name + signature):	Wei Qingyuan	魏水媛
☐ Testing procedure: TMP		N/A	
Testing location/ address::		N/A	
Test	ed by (name + signature):	N/A	
Арр	roved by (name + signature):	N/A	
		,.	
Testing procedure: WMT		N/A	
Testing location/ address:		N/A	
Test	ed by (name + signature):	N/A	
Witn	nessed by (name + signature):	N/A	
Арр	roved by (name + signature):	N/A	
☐ Testing procedure: SMT		N/A	
Testing location/ address:		N/A	
Test	ed by (name + signature):	N/A	
Арр	roved by (name + signature):	N/A	
Sup	ervised by (name + signature):	N/A	